

RELIABILITY MONITOR

PROCESS: 0.6 μ m Double Poly, Single Metal (Ti/TiN layers used on all Metals)

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2502	C2	DEC '98	P23041	9842	CARSEM	DM821478AIB	8 PIN SOIC	48	228	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2502	C2	DEC '98	P23123	9842	CARSEM	DM821478AIB	8 PIN SOIC	336	77	0
DS2502	C2	DEC '98	P23123	9842	CARSEM	DM821478AIB	8 PIN SOIC	1000	77	0

TOTALS FOR: 0.6 μ m Double Poly, Single Metal (Ti/Ti) FAIL RATE (Fits): 30 DEVICE HRS: 3.07E+07 0

RELIABILITY MONITOR

PROCESS: 0.6 μ m Single Poly, Single Metal (Ti/TiN layers used on all Metals)

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR	DATE	ASSEMBLY	LOT NO.	PACKAGE	READ	QTY	FAILS	
		DATE	JOB NO	CODE	FACILITY		POINT			
DS2401	C2	TO-92 MA	P23371	9851	CARSEM	DM832008AIA	TO-92	48	234	0

TOTALS FOR: 0.6 μ m Single Poly, Single Metal (Ti/Ti) FAIL RATE (Fits): 635 DEVICE HRS: 1.44E+06 0

RELIABILITY MONITOR

PROCESS: 0.8 μ m Double Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153	A7	DEC '98	P23108	9833	ANAM-K (ASI/AICL)	DN811539AAB	44 PIN PLCC	48	237	0
DS87C520	A13	NOV '98	P23309	9832	ANAM-K (ASI/AICL)	DN821500AAB	44 PIN PLCC	48	236	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2153	A7	DEC '98	P23191	9833	ANAM-K (ASI/AICL)	DN811539AAB	44 PIN PLCC	1000	77	0

TOTALS FOR: 0.8 μ m Double Poly, Single Metal FAIL RATE (Fits): 60 DEVICE HRS: 1.53E+07 0

RELIABILITY MONITOR

PROCESS: 0.8 μ m Single Poly, Double Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A3	SEP '98	P22691	9829	ANAM-PI (ATP/AAP)	DK817643AC	8 PIN PDIP	48	234	0
DS2118M	A4	MARCH'9	P23526	9904	ANAM-K (ASI/AICL)	DN844402AAC	36PN SSOP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1302	A3	SEP '98	P22734	9829	ANAM-PI (ATP/AAP)	DK817643AC	8 PIN PDIP	336	77	0
DS1302	A3	SEP '98	P22734	9829	ANAM-PI (ATP/AAP)	DK817643AC	8 PIN PDIP	1000	77	0

TOTALS FOR: 0.8 μ m Single Poly, Double Metal FAIL RATE (Fits): 72 DEVICE HRS: 1.28E+07 0

RELIABILITY MONITOR

PROCESS: 0.8 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232L	C2	JAN '99	P23139	9848	CHIPPAC, KOREA	DL832093AAA	8 PIN SOIC	48	234	0
DS1232L	C1	OCT '98	P22755	9830	CHIPPAC, KOREA	DL817678ABB	8 PIN SOIC	48	232	0
DS1620	D1	SEP '98	P22599	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	48	230	0
DS2109	A7	DEC '98	P23110	9836	CARSEM	DM811524AA-	28 PIN SOIC	48	233	0
DS21S07A	B2	NOV '98	P22912	9825	ANAM-PI (ATP/AAPI)	DK809216AC	20 PIN TSSOP	48	231	0
DS2401	B2	DEC '98	P22908	9815	CARSEM	DM803085AA	TO-92	48	234	0
DS2434	D1	NOV '98	P22801	9827	CARSEM	DM809170AA	TO-226 (PR-35)	48	237	0
DS80C320	B5	JAN '99	P23075	9841	ANAM-PI (ATP/AAPI)	DK827694AA	40 PIN PDIP	48	234	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232L	C2	JAN '99	P23184	9848	CHIPPAC, KOREA	DL832093AAA	8 PIN SOIC	336	77	0
DS1232L	C1	OCT '98	P22778	9830	CHIPPAC, KOREA	DL817678ABB	8 PIN SOIC	336	77	0
DS1232L	C2	JAN '99	P23184	9848	CHIPPAC, KOREA	DL832093AAA	8 PIN SOIC	1000	77	0
DS1232L	C1	OCT '98	P22778	9830	CHIPPAC, KOREA	DL817678ABB	8 PIN SOIC	1000	77	0
DS1620	D1	SEP '98	P22707	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	336	77	0
DS1620	D1	SEP '98	P22707	9746	ALPHTK-BANGKOK(NSE	DJ711527ABD	8PN SOIC, 208MIL	1000	77	0
DS2109	A7	DEC '98	P23155	9836	CARSEM	DM811524AA-	28 PIN SOIC	336	77	0
DS2109	A7	DEC '98	P23155	9836	CARSEM	DM811524AA-	28 PIN SOIC	1000	77	0

RELIABILITY MONITOR

DS21S07A	B2	NOV '98	P23127	9825	ANAM-PI (ATP/AAPI)	DK809216AC	20 PIN TSSOP	336	77	0
DS21S07A	B2	NOV '98	P23127	9825	ANAM-PI (ATP/AAPI)	DK809216AC	20 PIN TSSOP	1000	77	0
DS2401	B2	DEC '98	P22922	9815	CARSEM	DM803085AA	TO-92	336	77	0
DS2401	B2	DEC '98	P22922	9815	CARSEM	DM803085AA	TO-92	1000	77	0
DS2434	D1	NOV '98	P22857	9827	CARSEM	DM809170AA	TO-226 (PR-35)	336	77	0
DS2434	D1	NOV '98	P22857	9827	CARSEM	DM809170AA	TO-226 (PR-35)	1000	77	0
DS80C320	B5	JAN '99	P23223	9841	ANAM-PI (ATP/AAPI)	DK827694AA	40 PIN PDIP	336	77	0
DS80C320	B5	JAN '99	P23223	9841	ANAM-PI (ATP/AAPI)	DK827694AA	40 PIN PDIP	1000	77	0

TOTALS FOR: **0.8 μm Single Poly, Single Metal** **FAIL RATE (Fits):** **4** **DEVICE HRS:** **2.27E+08** **0**

RELIABILITY MONITOR

PROCESS: 1.2 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1000	E3	JAN '99	P23057	9847	CHIPPAC, CHINA (CPS)	DH833179ADA	8 PIN PDIP	48	234	0
DS1233	A5	JAN '99	P23164	9842	CARSEM	DM823017AB	SOT-223	48	229	0
DS1233	A5	OCT '98	P22753	9836	CARSEM	DM819258AC	SOT-223	48	229	0
DS1267	A1	NOV '98	P23026	9823	ANAM-PI (ATP/AAPI)	DK803107AAE	20 PIN TSSOP	48	233	0
DS2165	B1	OCT '98	P22757	9837	ANAM-K (ASI/AICL)	DN811583AAB	28 PIN PLCC	48	236	0
DS5002	B3	OCT '98	P22751	9831	CARSEM	DM817638AAF	80 PIN PQFP	48	198	0
DS5002	B3	JAN '99	P23122	9846	CARSEM	DM830493AA	80 PIN PQFP	48	199	1

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5	JAN '99	P23250	9842	CARSEM	DM823017AB	SOT-223	336	77	0
DS1233	A5	OCT '98	P22782	9836	CARSEM	DM819258AC	SOT-223	336	77	0
DS1233	A5	JAN '99	P23250	9842	CARSEM	DM823017AB	SOT-223	1000	77	0
DS1233	A5	OCT '98	P22782	9836	CARSEM	DM819258AC	SOT-223	1000	77	0
DS5002	B3	OCT '98	P22769	9831	CARSEM	DM817638AAF	80 PIN PQFP	336	77	0
DS5002	B3	JAN '99	P23229	9846	CARSEM	DM830493AA	80 PIN PQFP	336	77	0
DS5002	B3	OCT '98	P22769	9831	CARSEM	DM817638AAF	80 PIN PQFP	1000	77	0
DS5002	B3	JAN '99	P23229	9846	CARSEM	DM830493AA	80 PIN PQFP	1000	77	1

RELIABILITY MONITOR

TOTALS FOR: 1.2 μm Single Poly, Single Metal FAIL RATE (Fits): 24 DEVICE HRS: 1.31E+08 2

RELIABILITY MONITOR

PROCESS: 2.0 μ m Single Poly, Single Metal

STRESS: INFANT LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2175	D1	JAN '99	P23183	9838	ANAM-PI (ATP/AAPI)	DK826585AA	16 PIN SOIC	48	234	0
DS2181A	A2	AUG '98	P22480	9808	ANAM-K (ASI/AICL)	DN751456AAC	44 PIN PLCC	48	237	0

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2181A	A2	AUG '98	P22918	9808	ANAM-K (ASI/AICL)	DN751456AAC	44 PIN PLCC	336	77	0
DS2181A	A2	AUG '98	P22918	9808	ANAM-K (ASI/AICL)	DN751456AAC	44 PIN PLCC	1000	77	0

TOTALS FOR: 2.0 μ m Single Poly, Single Metal FAIL RATE (Fits): 26 DEVICE HRS: 3.46E+07 0